

**Search Notes**

Application/Control No.

10/720,030

Examiner

Daniel Pan

Applicant(s)/Patent under  
Reexamination

HEISHI ET AL.

Art Unit

2183

**SEARCHED**

Class	Subclass	Date	Examiner
712	210 213	12/21/2007	DP

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
west pgp uspat jpoabs epoabs derwent IEEE IBM NPL 710/305-307 711/172 712/207, 225	12/21/2007	DP